Test Report No. AERF/MAL/ 2878/2017

Date : ....16..../.06./2017

NABL ACCR. LAB

Certificate No. T - 0980

TEST REPORT

ON

SMF VRLA BATTERY

OB 1B-12

12V / 1B Ah

Material Appraisal Laboratory

ASSOCIATED ELECTRONICS
RESEARCH FOUNDATION

C-53, Phase-II,
Noida-201 305
Distt. Gautam Budh Nagar (U.P.)

E-mail : aerfnoida@yahoo.in
Website : www.aerfindia.com

Telefax : 0120-3047725 / 726
0120-3047727 / 728
0120-3047729
0120-2562355/2233

Phones : 0120 - 4543789, 4543790
E-mail : aerf@aerfindia.com,
aerfnoida@yahoo.in
Web. : www.aerfindia.com
CIN : U00000DL1981NPL011318

T-0483 T-0980

Associated Electronics Research Foundation

C-53, Phase-II Noida-201 305
(Recognised by DSIR, Govt. of India)
Centre for Research, Calibration & Testing
(An NABL Accredited Laboratory in Electrical & Electronics Testing)

Test Report

Test Report Number	Date	Page No.
AERF/MAL/2878/2017	16/06/2017	1 of 3

1. INDENTOR (Name & address of the organisation sending items for testing)	:	OKAYA Power Pvt Ltd. D- 7, Udyog Nagar, Rohtak Road, New Delhi – 110041
2. Indentor 's reference(Date of Receipt)	:	12/ 06 /2017
3. Description and identification of the item(as provided by the indentor)		
i) Nomenclature of the product	:	SMF / VRLA Battery
ii) Model/Sr No.	:	OB 18-12
iii) Value/Tolerance	:	12 V / 18Ah / 20Hrs
iv) Serial No.	:	IAUSS06201004855 & IAUSS06201004859
v) Manufacturer's name	:	OKAYA Power Pvt Ltd
vi) Year of manufacture	:	2017
vii) Trade Mark/Make	:	OKAYA
viii) Number of samples	:	Qty 2
ix) Condition of samples when submitted	:	Ok
4. a) Applicable Specification	:	As per JIS C 8702- (Part 1) : 2009
b) Samples were grouped and numbered as under	:	As per indentor
c) Environmental Conditions	:	26°C / 57% R.H
d) Date of Performance of Test:	:	12/06/2017 to 16/06/2017
5. Deviation if, any	:	None

Authorized Signatory

POOJA JAIN
Quality Manager
Associated Electronics Research Foundation
C-53, Phase-II, NOIDA U.P.-201305

Associated Electronics Research Foundation
C - 53
Phash - II
NOIDA
U.P.

Phones : 0120 - 4543789, 4543790
E-mail : aerf@aerfindia.com,
aerfnoida@yahoo.in
Web. : www.aerfindia.com
CIN : U00000DL1981NPL011318

T-0463 T-0980

Associated Electronics Research Foundation

C-53, Phase-II Noida-201 305
(Recognised by DSIR, Govt. of India)
Centre for Research, Calibration & Testing
(An NABL Accredited Laboratory in Electrical & Electronics Testing)

Test Report

Test Report Number	Date	Page No.
AERF/MAL/2878 /2017	16/06/2017	2 of 3

6. **Tests Conducted :**

Sr No	Test Parameter	Test Standard with Cl No	Test Condition	Observation with test data	Pass / Fail	Remarks
1	**Capacity 20 hrs**	As per JIS C 8702-1 : 2009 Cl 5.1 (a) & 7.1	After fully charged as per JIS C 8702-1: 2009, Cl 6.1 battery kept for 5 to 24 hrs at 25˚C ±2˚C discharge current I_{20} = 0.9 amp& final voltage 6 x 1.75 = 10.5V Capacity = t x I_{20}	Time taken to reach 10.5V End of voltage is 23.93hr Capacity = 23.93hr x 0.9A = 21.54Ah	Pass	
2	**High Rate Discharge**	As per JIS C 8702-1 : 2009 Cl 5.2 & 7.2	Discharge Current 20 x I_{20}= 18Amp. End of Voltage 9.6Volt. At 25˚C±2˚C discharge time should be 27 mins minimum	Discharge time for end of voltage 9.6Volt is 38.56 mins	Pass	

Associated Electronics Research Foundation C-53 Phase-II NOIDA U.P.

Authorized Signatory

Quality Manager
Associated Electronics Research Foundation
C-53, Phase-II, NOIDA U.P.-201305

T-0463 T-0980

Phones : 0120 - 4543789, 4543790
E-mail : aerf@aerfindia.com,
aerfnoida@yahoo.in
Web. : www.aerfindia.com
CIN : U00000DL1981NPL011318

Associated Electronics Research Foundation

C-53, Phase-II Noida-201 305
(Recognised by DSIR, Govt. of India)
Centre for Research, Calibration & Testing
(An NABL Accredited Laboratory in Electrical & Electronics Testing)

Test Report

Test Report Number	Date	Page No.
AERF/MAL/2878/2017	16/06/2017	3 of 3

7. **Remarks :**

1. This Report refers to the particular item submitted for testing.
2. This Report shall not be reproduced, except in full, unless written permission for the publication of an approved abstract has been obtained from the Authorised Signatory of ASSOCIATED ELECTRONICS RESEARCH FOUNDATION, NOIDA.
3. The results reported in the report are valid at the time of and under the stated conditions of measurement.

Associated Electronics Research Foundation
C - 53
Phash - II
NOIDA
U.P.

Authorized Signatory

POOJA JAIN
Quality Manager
Associated Electronics Research Foundation
C-53, Phase-II, NOIDA U.P.-201305